



Advanced Technology Related to Radar Signal, Imaging, and Radar Cross-Section Measurement

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Message from the Guest Editors

A radar system is made of many elemental and hard/software technologies. Recent applications are expanding to short distance radar, such as security, nondestructive observation, and aerial monitoring, as well as long distance radar, such as remote-sensing, surveillance, and weather observation. In these various applications, the key technologies supporting radar are essentially the signal, image, and data processing in order to detect a target more explicitly, which includes synthetic aperture imaging, compressive sensing, multiple input multiple output (MIMO) processing, and radar beam scanning, in a broad sense. On the other hand, radar cross-section (RCS) evaluation and electromagnetic modeling technologies of radar targets are also important to develop future smart radar.

The aim of this Special Issue of *Electronics* is to present state-of-the-art investigations in various radar-important technologies for future applications. We invite researchers to contribute original and unique articles, as well as sophisticated review articles.





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Message from the Editor-in-Chief

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